

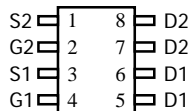
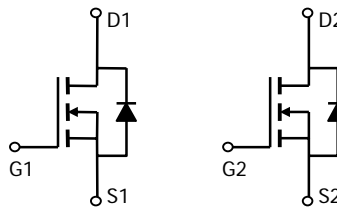
**AO4818B**
**Dual N-Channel Enhancement Mode Field Effect Transistor**
**General Description**

The AO4818B uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. *Standard Product AO4818B is Pb-free (meets ROHS & Sony 259 specifications).*

**Features**

$V_{DS} (V) = 30V$   
 $I_D = 8.5A (V_{GS} = 10V)$   
 $R_{DS(ON)} < 16m\Omega (V_{GS} = 10V)$   
 $R_{DS(ON)} < 26m\Omega (V_{GS} = 4.5V)$

UIS TESTED!  
 $R_g, C_{iss}, C_{oss}, C_{rss}$  Tested


**SOIC-8**

**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>AF</sup>	$I_D$	$T_A=25^\circ C$	8.5
		$T_A=70^\circ C$	6.6
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	A
Power Dissipation	$P_D$	$T_A=25^\circ C$	2
		$T_A=70^\circ C$	1.28
Avalanche Current <sup>B</sup>	$I_{AR}$	16	A
Repetitive avalanche energy 0.3mH <sup>B</sup>	$E_{AR}$	38	mJ
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

**Thermal Characteristics**

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	48	62.5	$^\circ C/W$
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	74	110
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	35	40	$^\circ C/W$

Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			1 5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V			100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.4	1.7	3	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	30			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =8.5A T <sub>J</sub> =125°C		13.4 20	16 25	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A		19.5	26	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =8.5A		23		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.75	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				3	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz		955	1250	pF
C <sub>oss</sub>	Output Capacitance			145		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			112		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		0.5	0.85	Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =8.5A		17	24	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge			9	12	nC
Q <sub>gs</sub>	Gate Source Charge			3.4		nC
Q <sub>gd</sub>	Gate Drain Charge			4.7		nC
t <sub>D(on)</sub>	Turn-On Delay Time			5	6.5	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, R <sub>L</sub> =1.8Ω, R <sub>GEN</sub> =3Ω		6	7.5	ns
t <sub>D(off)</sub>	Turn-Off Delay Time			19	25	ns
t <sub>f</sub>	Turn-Off Fall Time			4.5	6	ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =8.5A, dI/dt=100A/μs		16.7	21	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =8.5A, dI/dt=100A/μs		6.7	10	nC

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

F: The current rating is based on the ≤ 10s junction to ambient thermal resistance rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

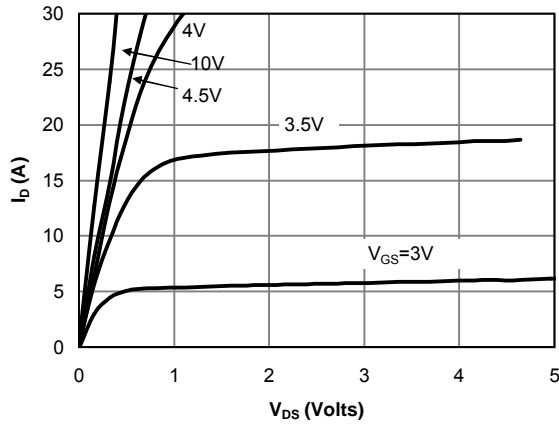


Fig 1: On-Region Characteristics

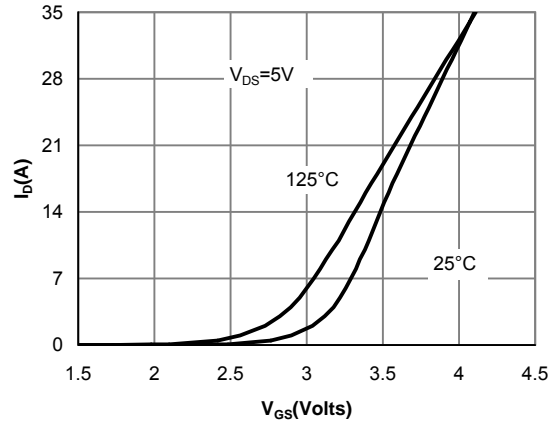


Figure 2: Transfer Characteristics

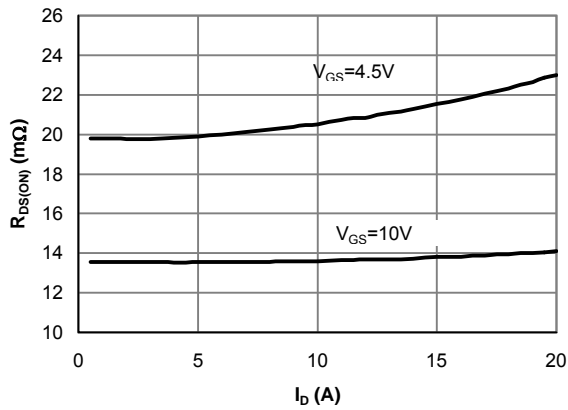


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

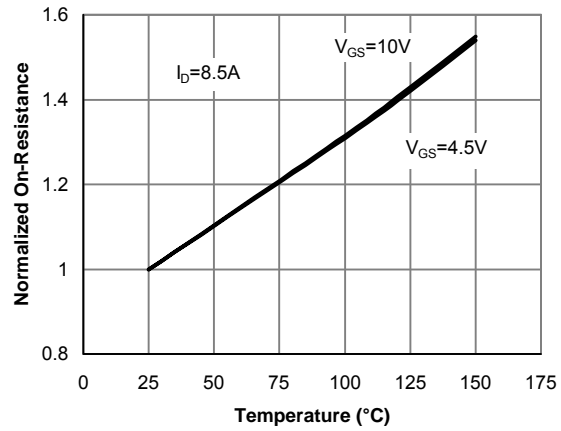


Figure 4: On-Resistance vs. Junction Temperature

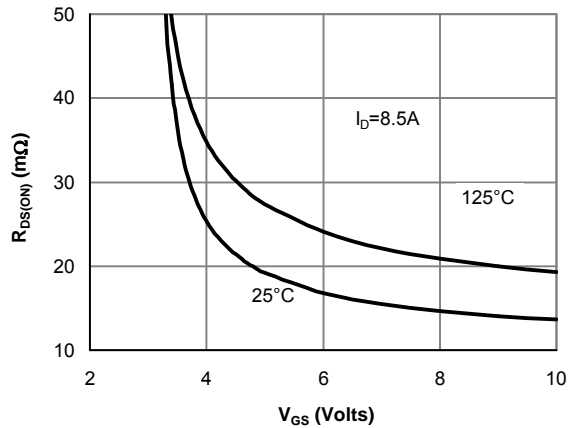


Figure 5: On-Resistance vs. Gate-Source Voltage

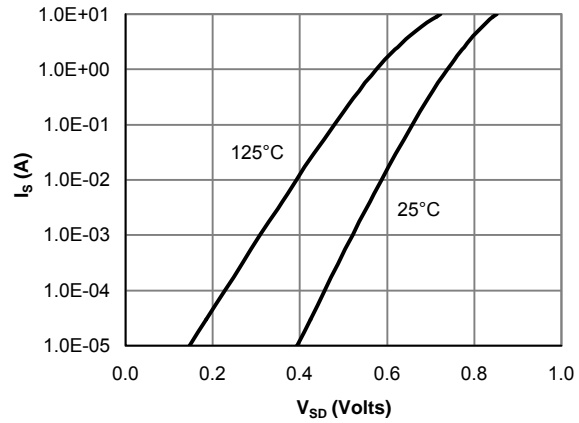


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

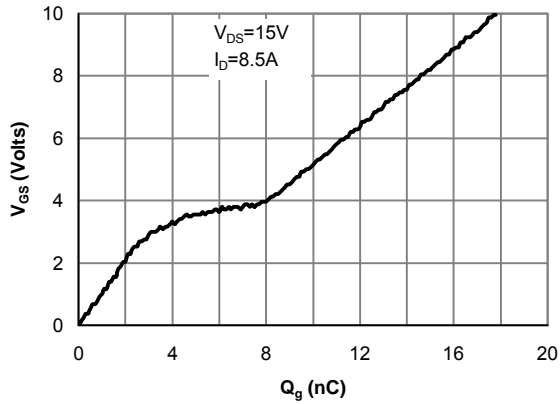


Figure 7: Gate-Charge Characteristics

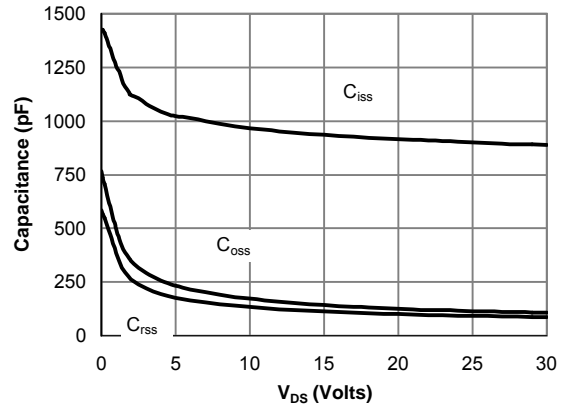


Figure 8: Capacitance Characteristics

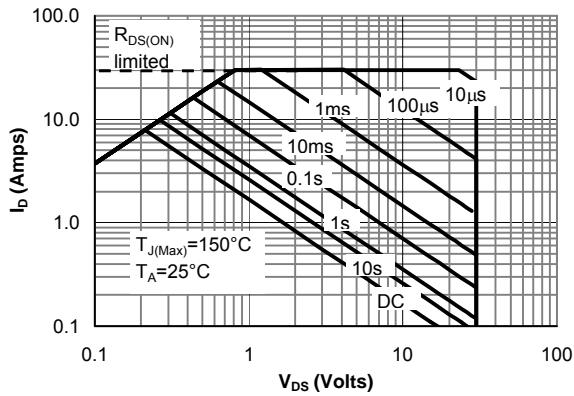


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

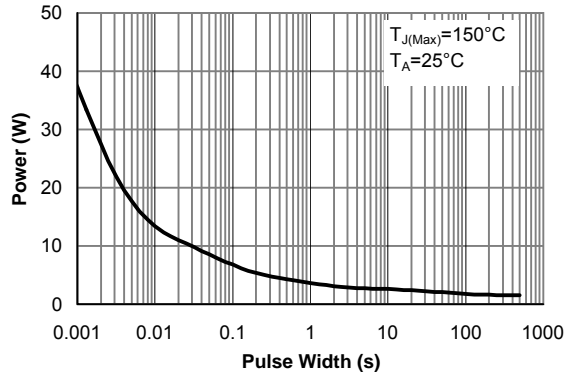


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

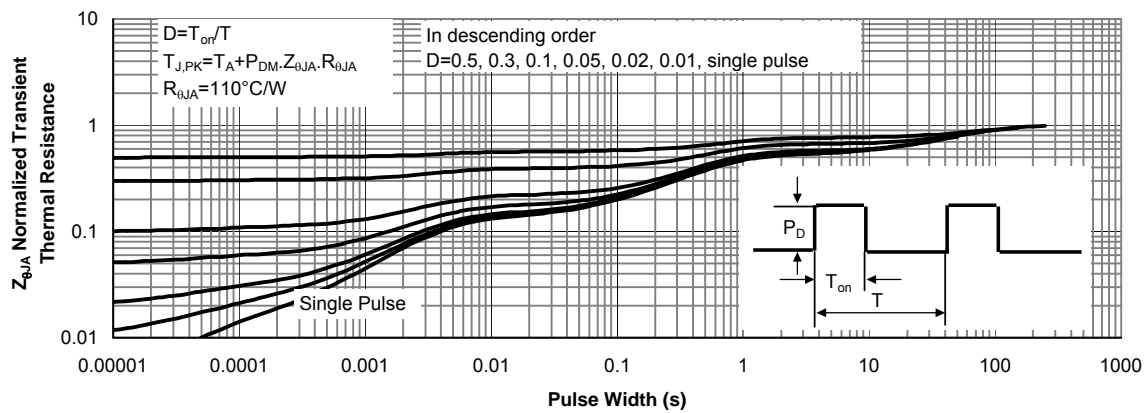
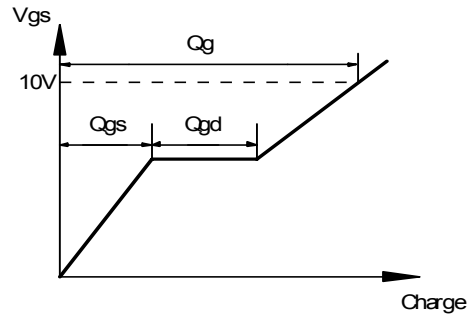
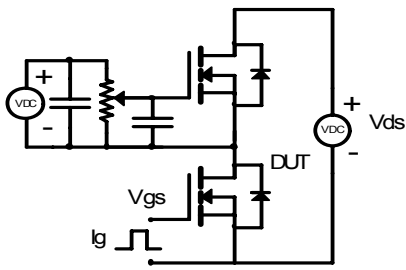
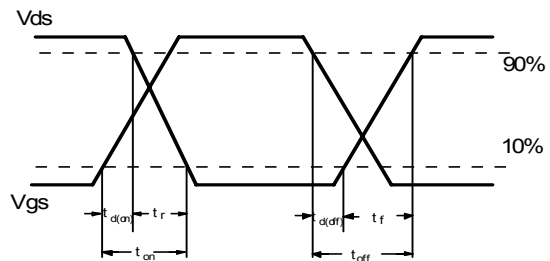
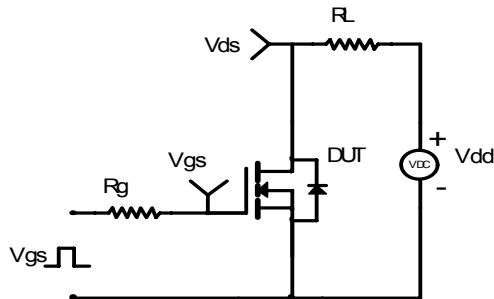


Figure 11: Normalized Maximum Transient Thermal Impedance

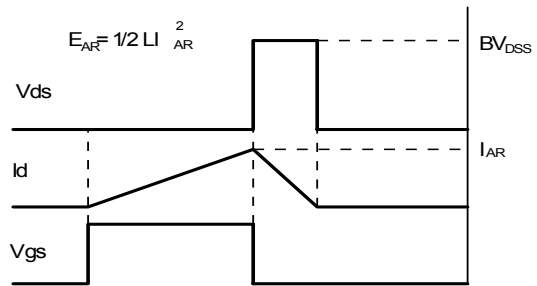
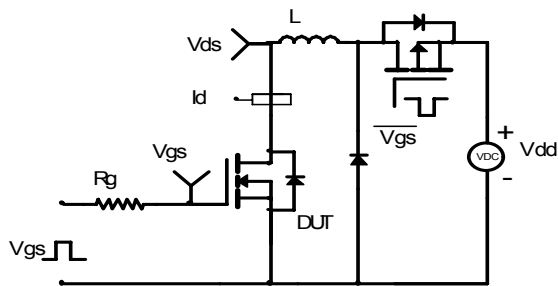
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

